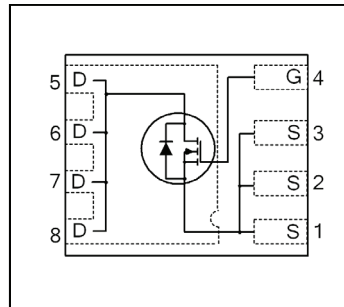


HEXFET® Power MOSFET

$V_{DSS}$	25	V
$R_{DS(on) \max}$ (@ $V_{GS} = 10V$ )	3.4	mΩ
(@ $V_{GS} = 4.5V$ )	4.6	
$Qg$ (typical)	9.7	nC
$I_D$ (@ $T_C$ (Bottom) = 25°C)	40 <sup>⑦</sup>	A



### Applications

- Control MOSFET for synchronous buck converter

### Features

Low Charge (typical 9.7nC)
Low $R_{DS(on)}$ (<3.4mΩ)
Low Thermal Resistance to PCB (<4.3°C/W)
Low Profile (<0.9mm)
Industry-Standard Pinout
Compatible with Existing Surface Mount Techniques
RoHS Compliant, Halogen-Free
MSL1, Industrial Qualification

results in

⇒

### Benefits

Low Switching Losses
Lower Conduction Losses
Enable better Thermal Dissipation
Increased Power Density
Multi-Vendor Compatibility
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFHM4231PbF	PQFN 3.3mm x 3.3mm	Tape and Reel	4000	IRFHM4231TRPbF

### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$I_D$ @ $T_A = 25^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V	22	A
$I_D$ @ $T_{C(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V	72 <sup>⑥⑦</sup>	
$I_D$ @ $T_{C(Bottom)} = 100^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V	46 <sup>⑥</sup>	
$I_D$ @ $T_C = 25^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V (Source Bonding Technology Limited)	40 <sup>⑦</sup>	
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	288	
$P_D$ @ $T_A = 25^\circ C$	Power Dissipation <sup>⑤</sup>	2.7	W
$P_D$ @ $T_{C(Bottom)} = 25^\circ C$	Power Dissipation	29	
	Linear Derating Factor	0.021	W/°C
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Notes <sup>①</sup> through <sup>⑦</sup> are on page 9

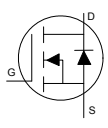
**Static @ T<sub>J</sub> = 25°C (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	25	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	22	—	mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	2.7	3.4	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A ③
		—	3.7	4.6		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 30A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.1	1.6	2.1	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 35μA
ΔV <sub>GS(th)</sub>	Gate Threshold Voltage Coefficient	—	-5.4	—	mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	1.0	μA	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -20V
g <sub>fs</sub>	Forward Transconductance	120	—	—	S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 30A
Q <sub>g</sub>	Total Gate Charge	—	20	—	nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 13V, I <sub>D</sub> = 30A
Q <sub>g</sub>	Total Gate Charge	—	9.7	15	nC	V <sub>DS</sub> = 13V V <sub>GS</sub> = 4.5V I <sub>D</sub> = 30A
Q <sub>gs1</sub>	Pre-V <sub>th</sub> Gate-to-Source Charge	—	1.9	—		
Q <sub>gs2</sub>	Post-V <sub>th</sub> Gate-to-Source Charge	—	1.2	—		
Q <sub>gd</sub>	Gate-to-Drain Charge	—	3.6	—		
Q <sub>godr</sub>	Gate Charge Overdrive	—	3.0	—		
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )	—	4.8	—		
Q <sub>oss</sub>	Output Charge	—	9.6	—	nC	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
R <sub>G</sub>	Gate Resistance	—	1.4	—	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time	—	8.7	—	ns	V <sub>DD</sub> = 13V, V <sub>GS</sub> = 4.5V I <sub>D</sub> = 30A R <sub>G</sub> = 1.8Ω
t <sub>r</sub>	Rise Time	—	28	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	12	—		
t <sub>f</sub>	Fall Time	—	5.9	—		
C <sub>iss</sub>	Input Capacitance	—	1270	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 13V f = 1.0MHz
C <sub>oss</sub>	Output Capacitance	—	360	—		
C <sub>rss</sub>	Reverse Transfer Capacitance	—	97	—		

**Avalanche Characteristics**

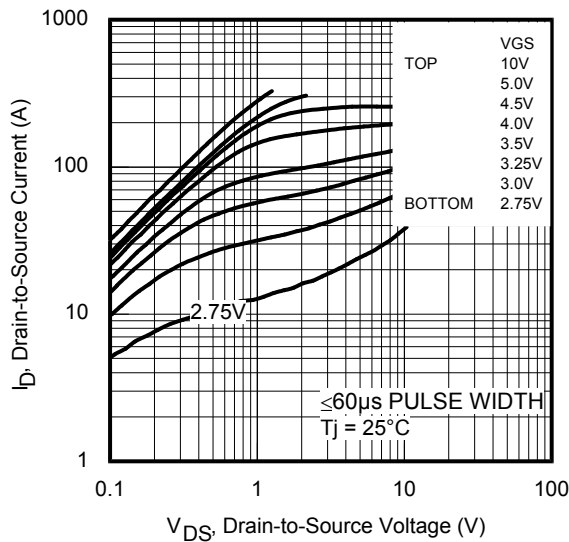
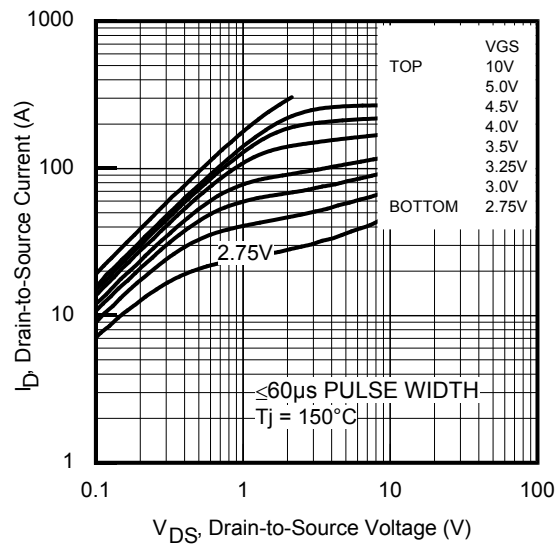
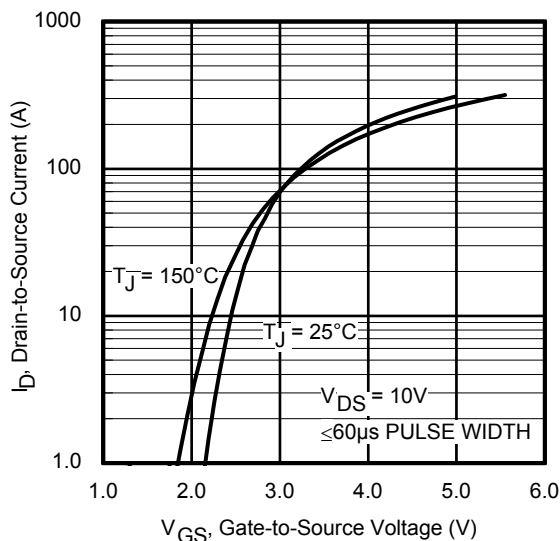
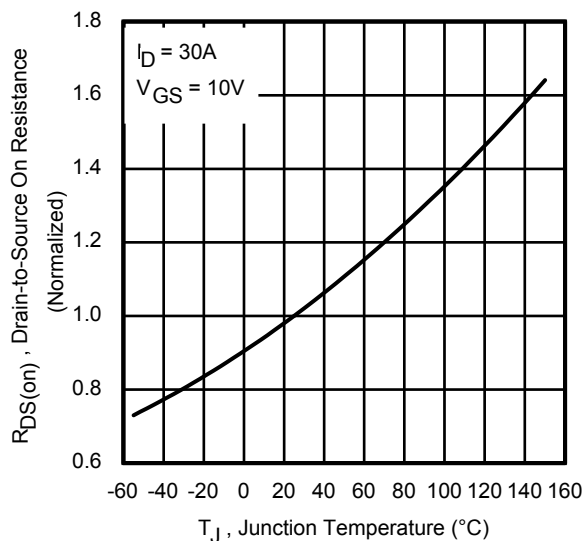
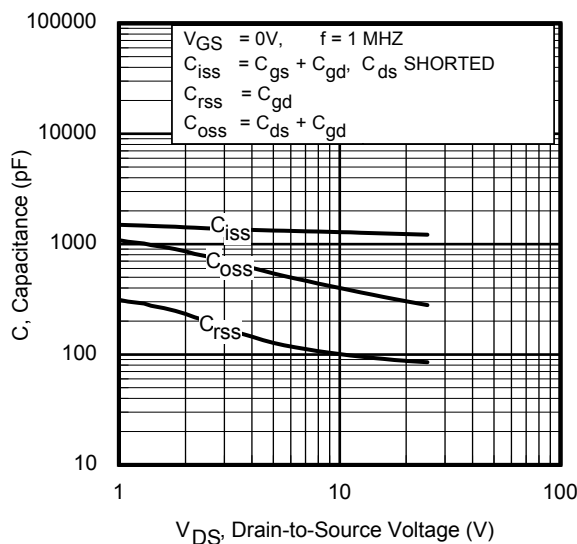
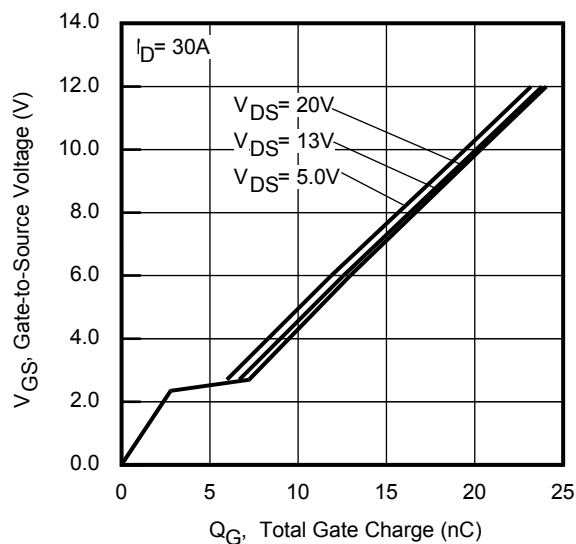
	Parameter	Typ.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	—	42	mJ
I <sub>AR</sub>	Avalanche Current ①	—	30	A

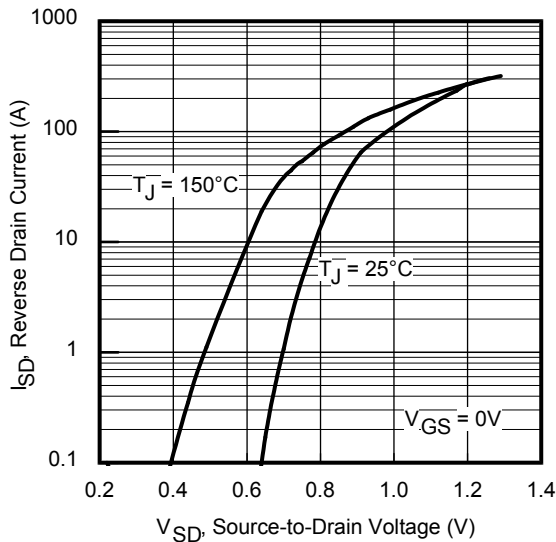
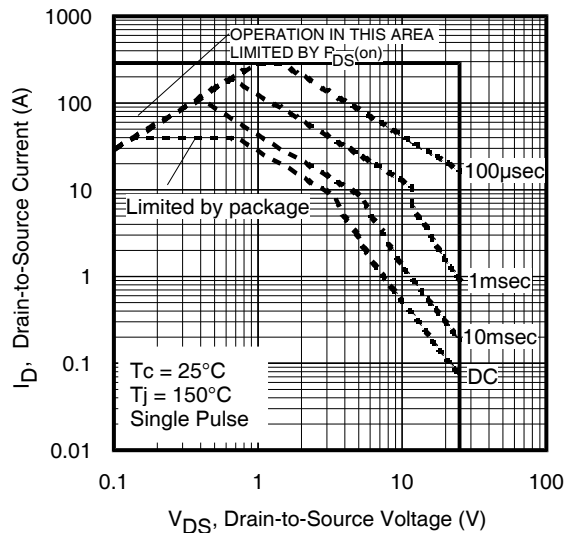
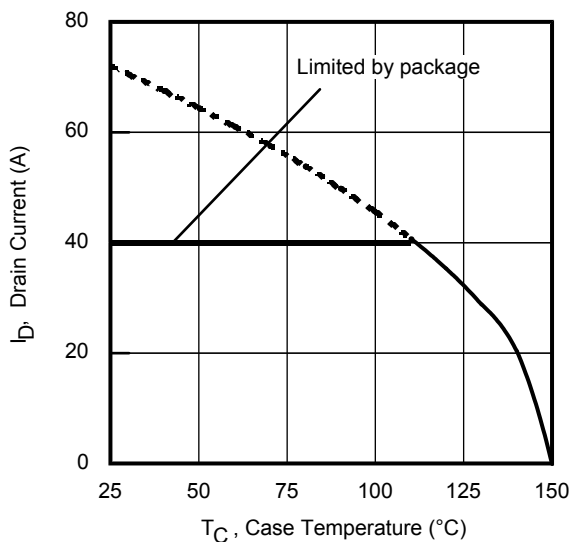
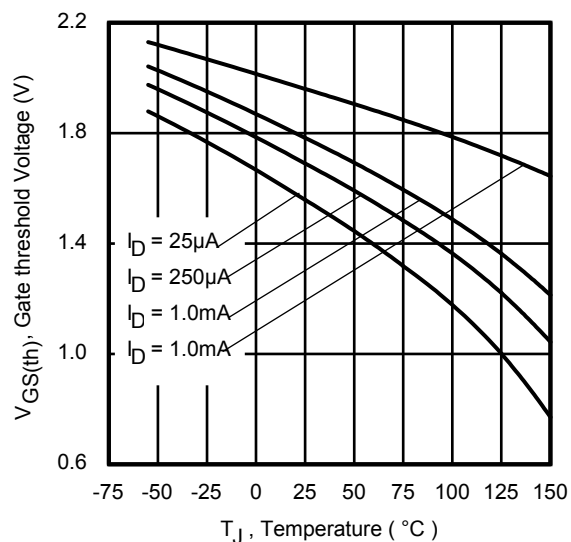
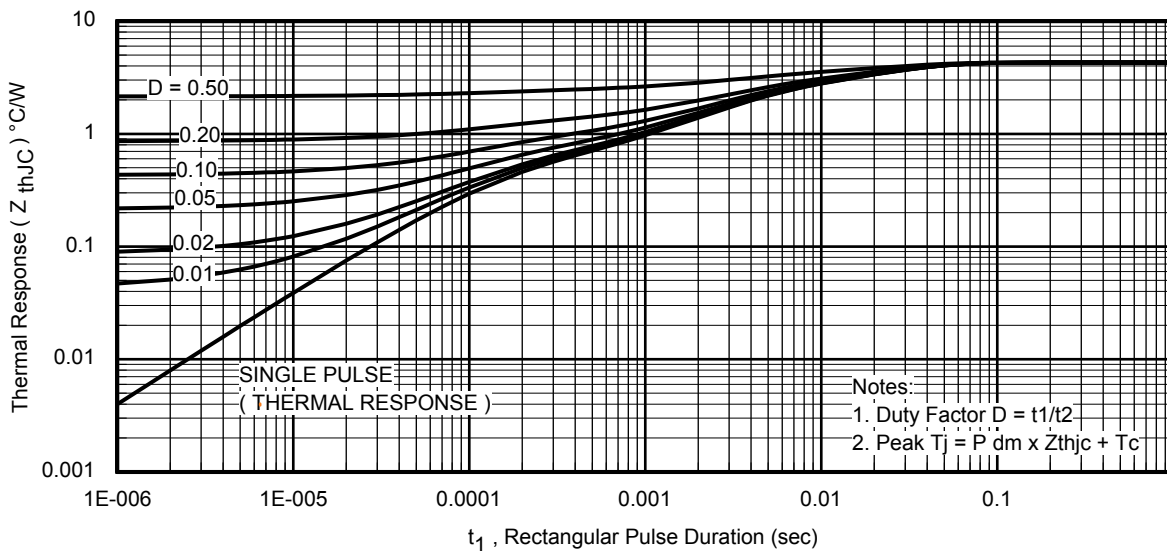
**Diode Characteristics**

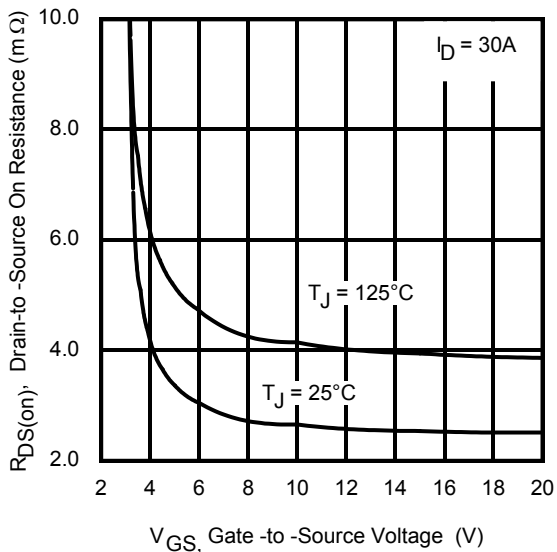
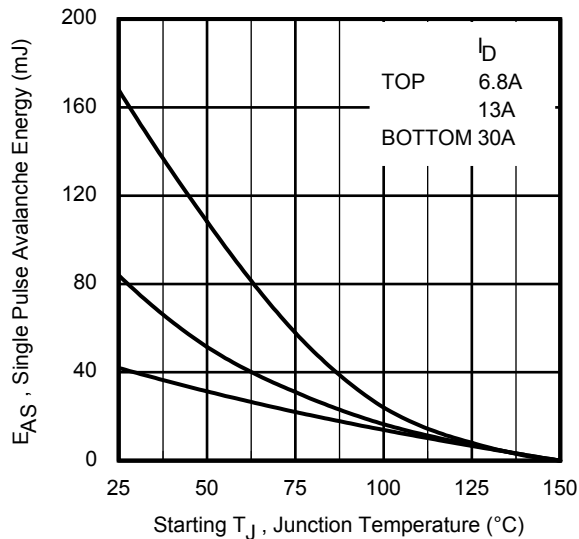
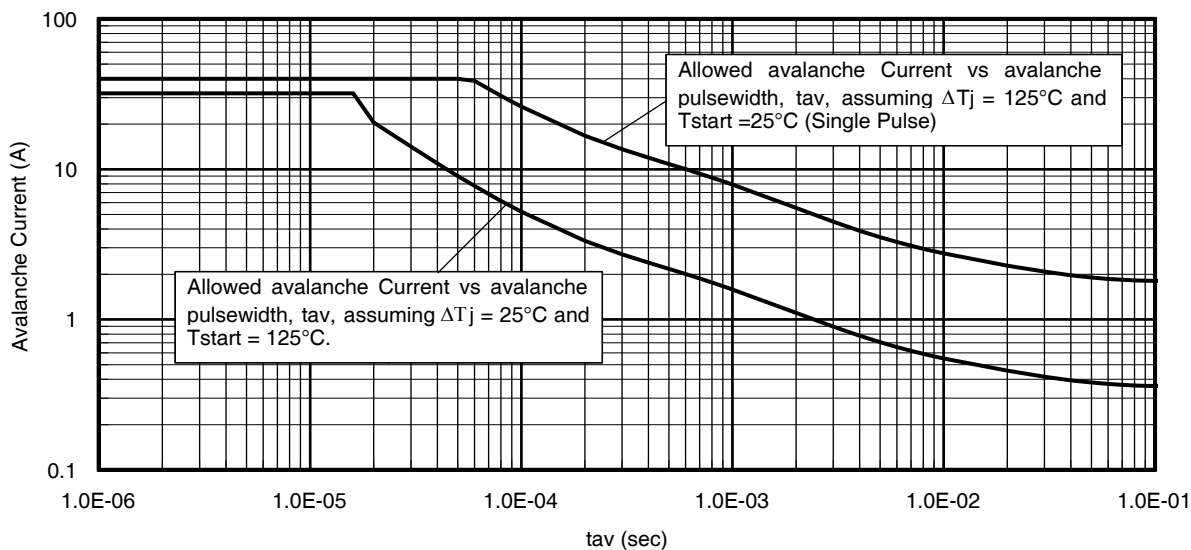
	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	40⑦	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	288		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.0	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 30A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time	—	16	24	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 30A, V <sub>DD</sub> = 13V
Q <sub>rr</sub>	Reverse Recovery Charge	—	13	20	nC	di/dt = 280A/μs ③

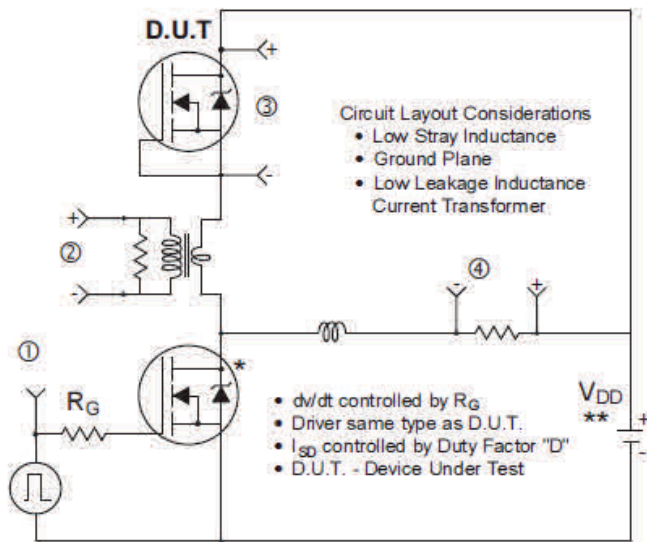
**Thermal Resistance**

	Parameter	Typ.	Max.	Units
R <sub>θJC</sub> (Bottom)	Junction-to-Case ④	—	4.3	°C/W
R <sub>θJC</sub> (Top)	Junction-to-Case ④	—	37	
R <sub>θJA</sub>	Junction-to-Ambient ⑤	—	47	
R <sub>θJA</sub> (<10s)	Junction-to-Ambient ⑤	—	31	


**Fig 1.** Typical Output Characteristics

**Fig 2.** Typical Output Characteristics

**Fig 3.** Typical Transfer Characteristics

**Fig 4.** Normalized On-Resistance vs. Temperature

**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

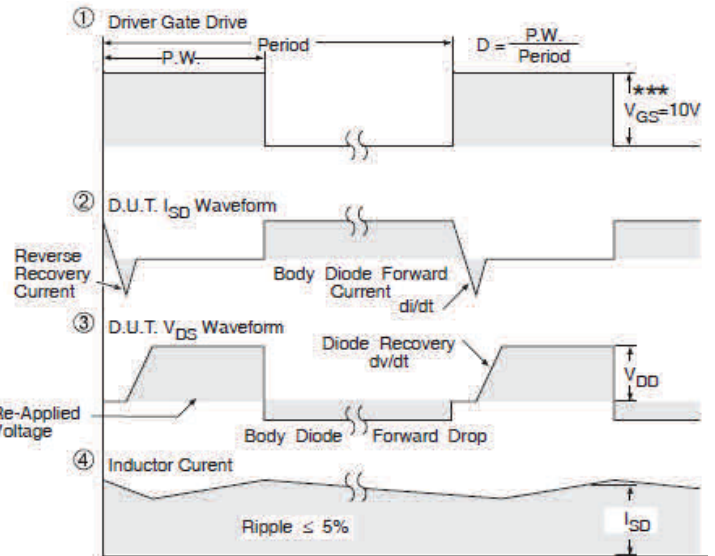

**Fig 7.** Typical Source-Drain Diode Forward Voltage

**Fig 8.** Maximum Safe Operating Area

**Fig 9.** Maximum Drain Current vs. Case Temperature

**Fig 10.** Drain-to-Source Breakdown Voltage

**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case


**Fig 12.** On-Resistance vs. Gate Voltage

**Fig 13.** Maximum Avalanche Energy vs. Drain Current

**Fig 14.** Typical Avalanche Current vs. Pulse Width

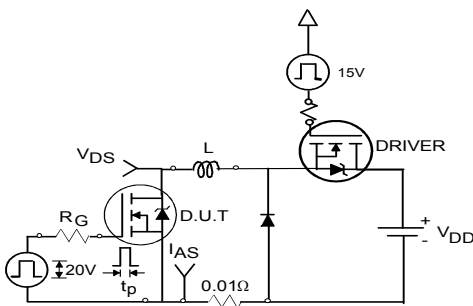


\* Use P-Channel Driver for P-Channel Measurements  
 \*\* Reverse Polarity for P-Channel

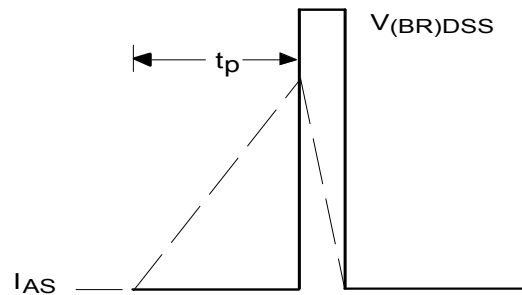
**Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs**



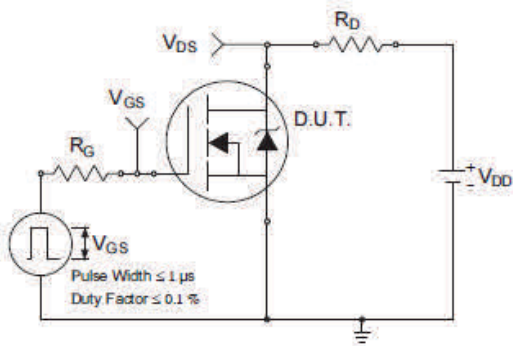
\*\*\*  $V_{GS} = 5V$  for Logic Level Devices



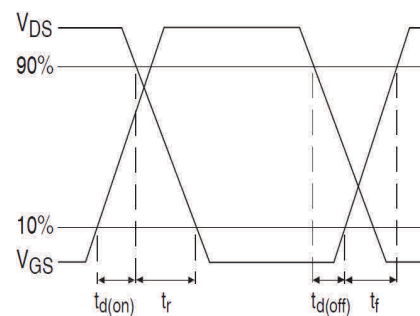
**Fig 16a. Unclamped Inductive Test Circuit**



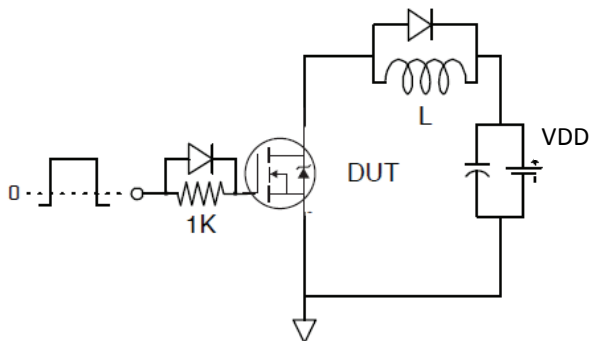
**Fig 16b. Unclamped Inductive Waveforms**



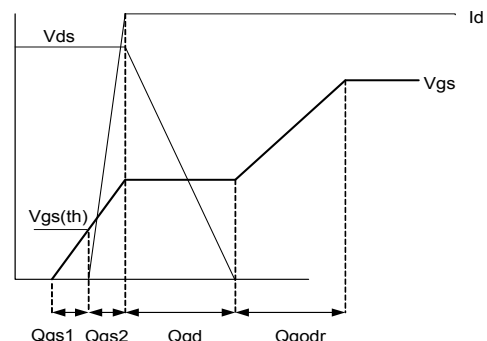
**Fig 17a. Switching Time Test Circuit**



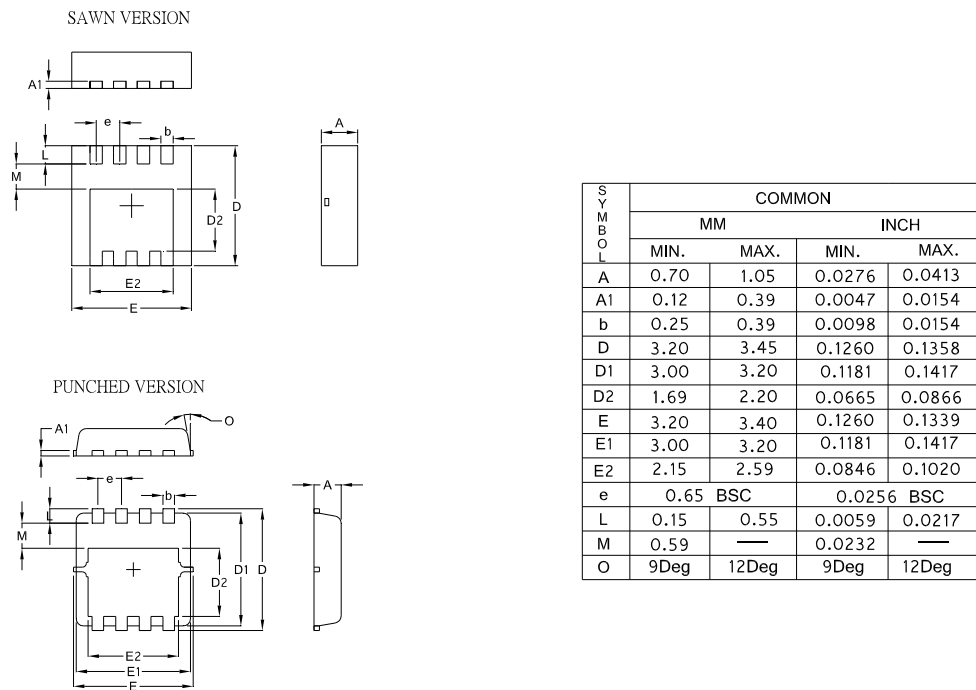
**Fig 17b. Switching Time Waveforms**



**Fig 18. Gate Charge Test Circuit**

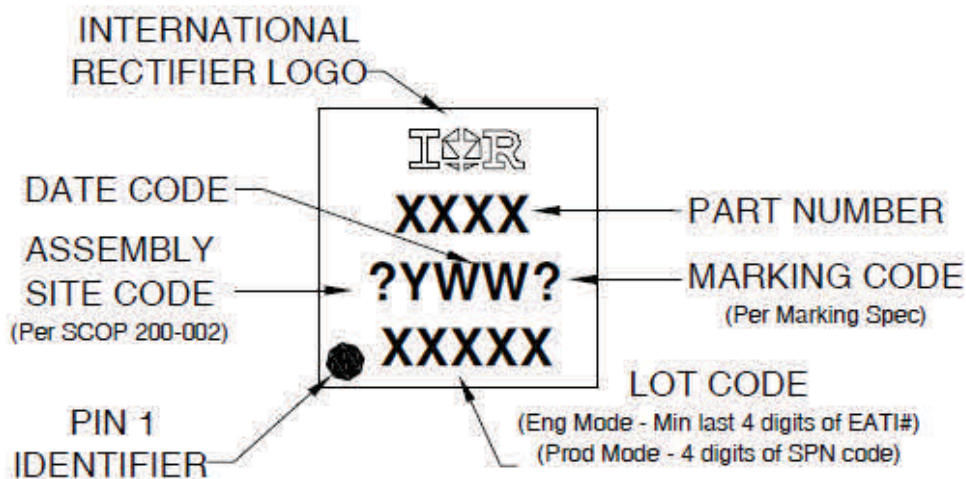


**Fig 19. Gate Charge Waveform**

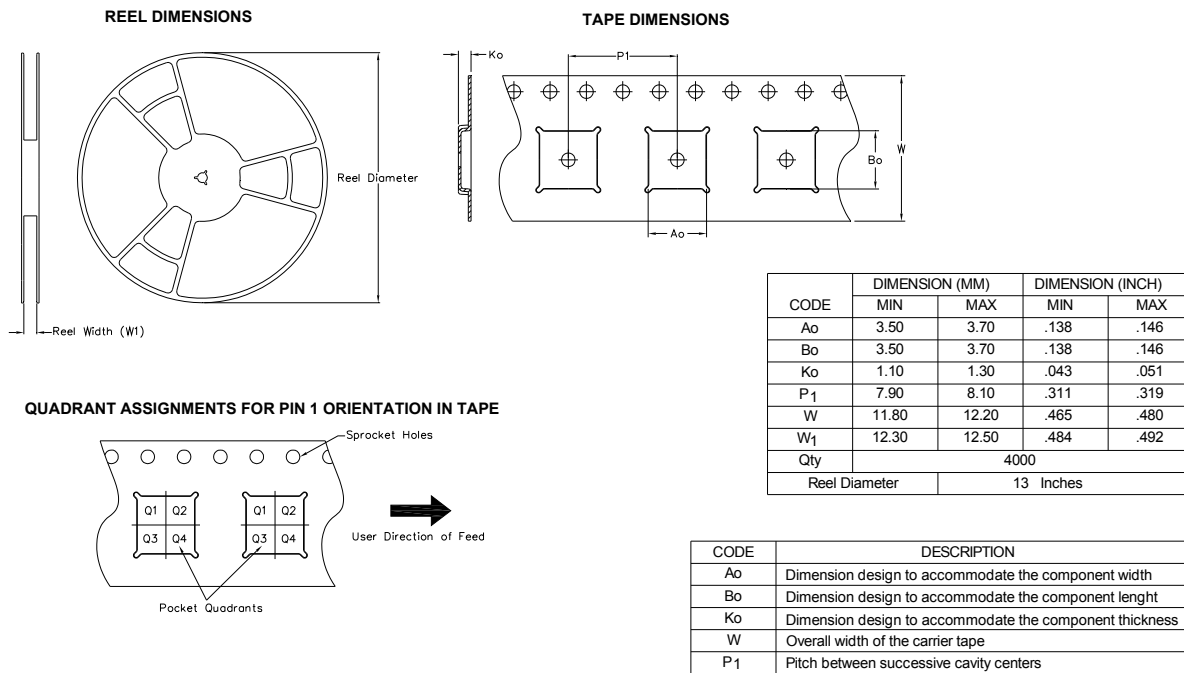
**PQFN 3.3 x 3.3 Package Details**


For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: <http://www.irf.com/technical-info/appnotes/an-1136.pdf>

For more information on package inspection techniques, please refer to application note AN-1154: <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

**PQFN 3.3 x 3.3 Part Marking**


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**PQFN 3.3 x 3.3 Tape and Reel**


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>



**Qualification Information†**

<b>Qualification Level</b>	Industrial (per JEDEC JESD47F†† guidelines)	
<b>Moisture Sensitivity Level</b>	PQFN 3.3mm x 3.3mm	MSL1 (per JEDEC J-STD-020D††)
<b>RoHS Compliant</b>	Yes	

† Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

†† Applicable version of JEDEC standard at the time of product release.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.093\text{mH}$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 30\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details:  
<http://www.irf.com/technical-info/appnotes/an-994.pdf>
- ⑥ Calculated continuous current based on maximum allowable junction temperature.
- ⑦ Current is limited to 40A by source bonding technology.

**Revision History**

<b>Date</b>	<b>Comments</b>
6/5/14	<ul style="list-style-type: none"> <li>• Updated schematic on page 1</li> <li>• Updated tape and reel on page 9</li> </ul>